

SHEET 1 OF 2

Form PTO 1449		U.S. DEPARTMENT	OF COMMERCE	ATTY DOCKET NO.		SERIAL NO.					
(Modified)		PATENT AND TRAD	EMARK OFFICE	245600US0		10/714,853					
				APPLICANT							
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Hideyuki OTSUKA, et al.							
				FILING DATE		GROUP					
				November 18, 2003							
U.S. PATENT DOCUMENTS											
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE					
16	AA	2001/0004667 A1	06/21/2001	M. OKUBO, et al.							
10	AB	5,529,872	06/25/1996	K. GRYCHTOL, et al.							
16	AC	5,204,453	04/20/1993	B. CHAMBON, et al.							
10	AD	2002/0156161 A1	10/24/2002	R. KOSHIDA, et al.							
			FO	REIGN PATENT DOCUMENTS							
		DOCUMENT	DATE	00111777			TRANSLATION				
		NUMBER	DATE	COUNTRY		YES					
10-	ΑE	WO 03/098617	11/27/2003	WIPO							
16	AF	2003-231843	08/19/2003	JAPAN							
10	AG	2004-2618	01/08/2004	JAPAN							
10	АН	2003-15364	01/17/2003	JAPAN .							
16	Al	2002-82481	03/22/2002	JAPAN							
16	AJ	2002-82480	03/22/2002	JAPAN .							
16	AL	2001-356526	12/26/2001	JAPAN							
10	AL	2001-194830	07/19/2001	JAPAN							
10	AM	11-133670	05/21/1999	JAPAN							
16	AN	10-48875	02/20/1998	JAPAN							
16	AO	0 977 093	02/02/2000	EUROPE							
10	AP	WO 94/03841	02/17/1994	WIPO (with English Abstract)			х				
1/4	AQ	60-106859	06/12/1985	JAPAN							
16	AR	60-107655	06/13/1985	JAPAN							
16	AS	2-305832	12/19/1990	JAPAN (with English Abstract)			x				
16	ΑT	43-17955	07/30/1968	JAPAN			х				
10	UA	43-27596	11/27/1968	JAPAN			X				
16	ΑV	57-167033	10/14/1982	JAPAN (with English Abstract)			x				
10	AW	8-500912	01/30/1996	JAPAN (with English Abstract and corr. US 5,529,872)			×				
10	AX	61-155464	07/15/1986	JAPAN (with English Abstract)			X				
16	AY	11-20317	01/26/1999	JAPAN (with English Abstract)			x				
16	ΑZ	5-192638	08/03/1993	JAPAN (with English Abstract)			x				
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					Additional References sheet(s) attached						
Examiner J Goodrow					Date Considered 9/03						
Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in											

SHEET 2 OF 2

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Form PTO 1449 (Modified)	,	U.S. SEP PRIME	OF COMMERCE DEMARK OFFICE	ATTY DOCKET NO.	SERIAL NO.			
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		DOCUMENT NUMBER	DATE	COUNTRY	V	TRANSLATION ES NO		
16	AA	7-32535	02/03/1995	JAPAN (with English Abstract)	-	ES NO X		
16-	AB	7-32540	02/03/1995	JAPAN (with English Abstract)		×		
15	AC	7-32539	02/03/1995	JAPAN (with English Abstract)				
-/-	AD	7-227570	08/29/1995	JAPAN (with English Abstract)		×		
10-	- AE	7-32538	02/03/1995	JAPAN (with English Abstract)		×		
16	AF	62-225563	10/03/1987	JAPAN (with English Abstract and corr. US 5,204,453)		×		
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Examiner	JGOOdrow Date Considered 9/05							
*Examiner: In conformance	itial if re and no	eference is considered, to considered. Include co	whether or not ppy of this form	t citation is in conformance with MPEP 60 with next communication to applicant.	09; Draw line through	n citation if not in		